

TECHNICAL BULLETIN # 10

April 20, 2012

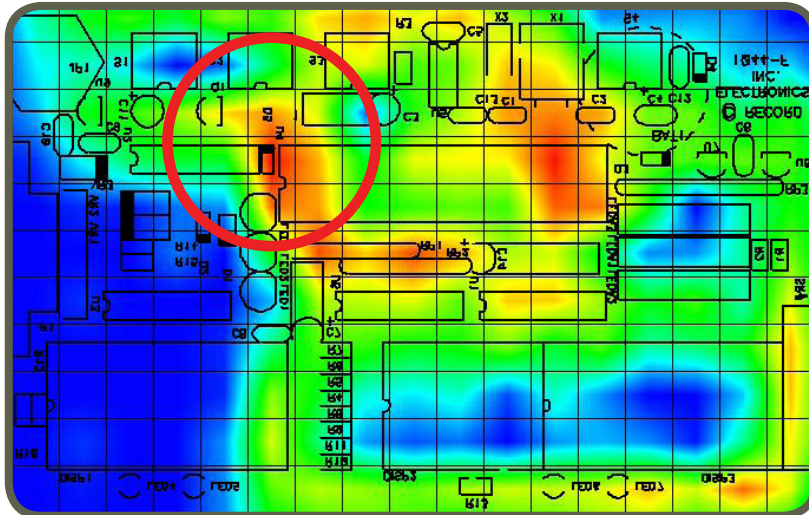
To: All EMxpert End-Users

Re: EMxpert Application - Handheld Probe Node

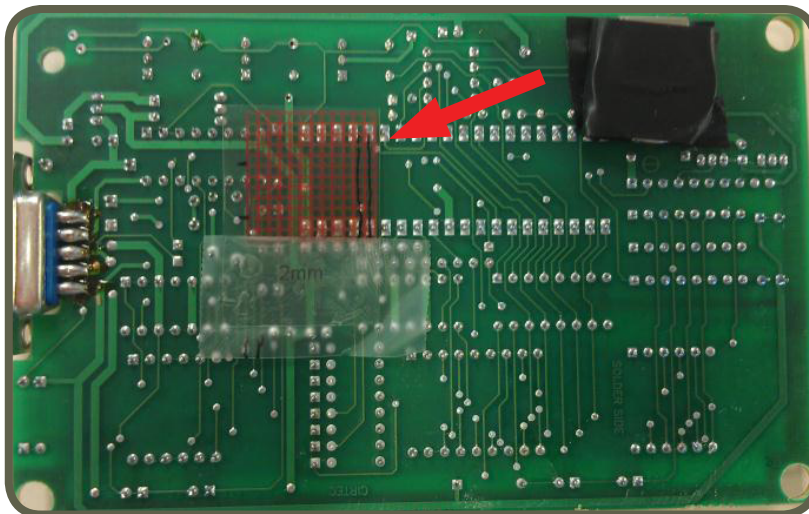
With Release 4.3 and above, the EMxpert application integrates any third-party hand-held magnetic or electric near-field probe to further assist PCB engineers in quickly meeting their EMC/EMI target levels.

A handheld probe can help pinpoint for example the source of emission down to a pin of any board component that was rapidly identified by the EMxpert scanner.

- Locate an area of the board where strong currents are located. This can identify current paths and large scale structures indicating current loops. Use the Blind Spot Reduction node to optimize coverage.

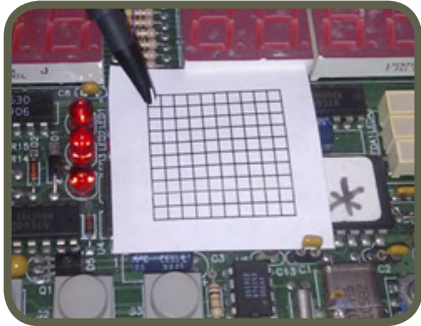


- Focus on a small area of the board for high resolution follow-up

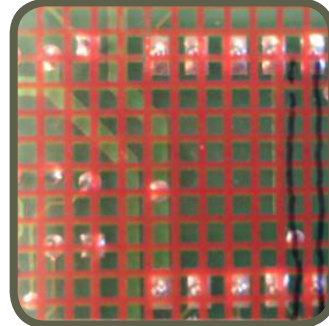


- Create a grid on paper or transparent plastic with a user-defined resolution to help with the positioning of the probe. Place the grid over the area to be tested and perform a Hand-held probe scan.

Here are some example of grids with 2 mm squares.

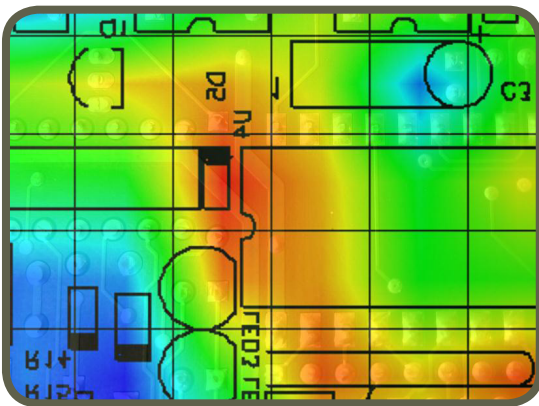


Component Side

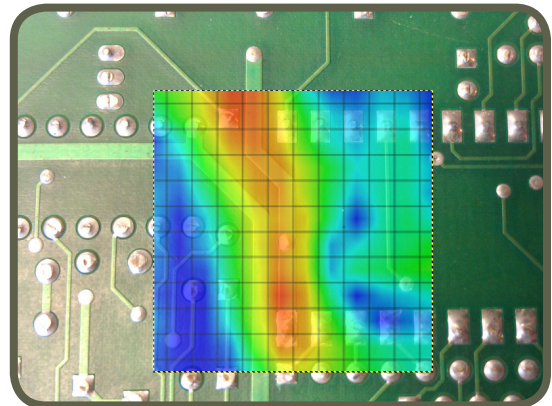


Bottom Side

- Analyze the new high resolution results with all the functionality and convenience of a regular spectral-spatial scan.



7.5 mm x 7.5 mm



2.0 mm x 2.0 mm